

Model	Field Emission Transmission Electron Microscope HF5000	Transmission Electron Microscope HT7800 With option	Transmission Electron Microscope HT7820 With option	Transmission Electron Microscope HT7830 With option
Electron source	W(310) cold field emission electron source	W,LaB ⁶ filament*		
Accelerating voltage	200 kV, 60 kV*	120 kV – 20 kV		
Resolution	ADF-STEM image 0.078 nm TEM lattice image 0.102 nm	Lattice 0.20 nm (Off-axis,100 kV)	Lattice 0.14 nm (Off-axis,100 kV)	0.14 nm (Off-axis, 120 kV) 0.19 nm (On-axis, 120 kV)
Magnification	STEM ×20 – ×8,000,000 TEM ×100 – ×1,500,000	x 600,000	x 800,000	×1,000,000
Specimen tilt angle	α=±25°, β=±35° (Hitachi double-tilt specimen holder*)	±70°	±30°	±10°